



2Mx32 5V Flash Module PRELIMINARY*

FEATURES

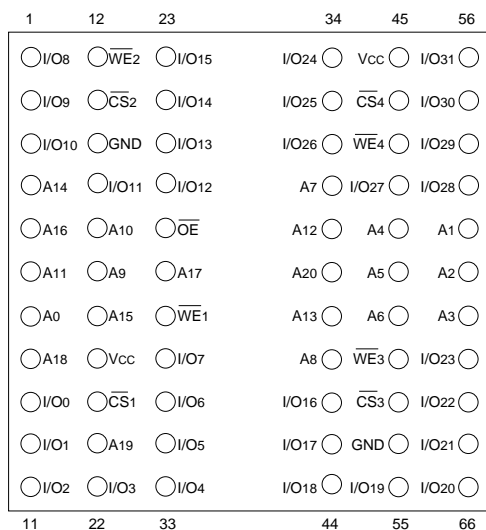
- Access Time of 90, 120, 150ns
- Packaging:
 - 66 pin, PGA Type, 1.185" square, Hermetic Ceramic HIP (Package 401).
 - 68 lead, Hermetic CQFP (G2U), 22.4mm (0.880") square (Package 510) 3.56mm (0.140") height. Designed to fit JEDEC 68 lead 0.990" CQFJ footprint (Fig. 3)
- Sector Architecture
 - 32 equal size sectors of 64KBytes per each 2Mx8 chip
 - Any combination of sectors can be erased. Also supports full chip erase.
- Minimum 100,000 Write/Erase Cycles Minimum
- Organized as 2Mx32
- Commercial, Industrial, and Extended Temperature Ranges
- 5 Volt Read and Write. 5V ± 10% Supply.
- Low Power CMOS
- $\overline{\text{Data}}$ Polling and Toggle Bit feature for detection of program or erase cycle completion.
- Supports reading or programming data to a sector not being erased.
- $\overline{\text{RESET}}$ pin resets internal state machine to the read mode.
- Built in Decoupling Caps and Multiple Ground Pins for Low Noise Operation, Separate Power and Ground Planes to improve noise immunity

* This data sheet describes a product under development, not fully characterized, and is subject to change without notice.

Note:
For programming information refer to Flash Programming 16M5 Application Note.

FIG. 1 PIN CONFIGURATION FOR WF2M32-XXH5

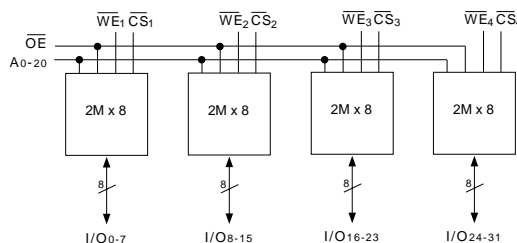
TOP VIEW



PIN DESCRIPTION

I/O0-31	Data Inputs/Outputs
A0-20	Address Inputs
$\overline{\text{WE}}_{1-4}$	Write Enables
$\overline{\text{CS}}_{1-4}$	Chip Selects
$\overline{\text{OE}}$	Output Enable
VCC	Power Supply
GND	Ground

BLOCK DIAGRAM

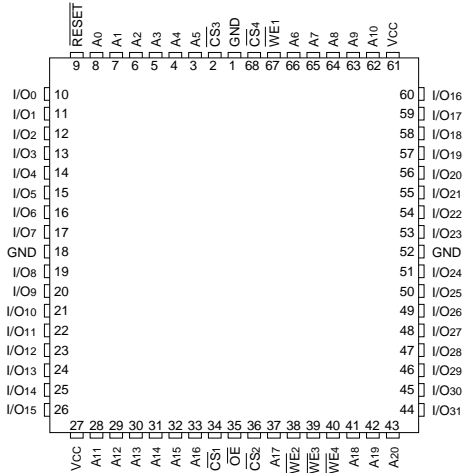


$\overline{\text{RESET}}$ internally tied to Vcc in the HIP package for this pin configuration. See Alternate Pin Configuration with $\overline{\text{RESET}}$ tied to pin 12 for system control of reset (Fig. 10, page 11).



FIG. 2 PIN CONFIGURATION FOR WF2M32-XG2UX5

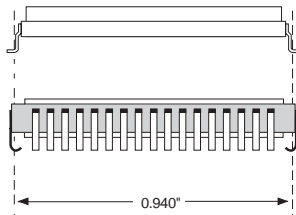
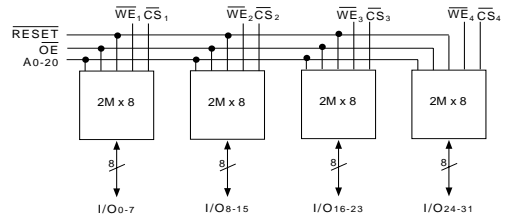
TOP VIEW



PIN DESCRIPTION

I/O0-31	Data Inputs/Outputs
A0-20	Address Inputs
\overline{WE}_{1-4}	Write Enables
\overline{CS}_{1-4}	Chip Selects
\overline{OE}	Output Enable
V _{CC}	Power Supply
GND	Ground
RESET	Reset

BLOCK DIAGRAM



The WEDC 68 lead G2U CQFP fills the same fit and function as the JEDEC 68 lead CQFJ or 68 PLCC. But the G2U has the TCE and lead inspection advantage of the CQFP form.



ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Ratings	Unit
Voltage on Any Pin Relative to V _{SS}	V _T	-2.0 to +7.0	V
Power Dissipation	P _T	8	W
Storage Temperature	T _{stg}	-65 to +125	°C
Short Circuit Output Current	I _{OS}	100	mA
Endurance - Write/Erase Cycles (Extended Temp)		100,000 min	cycles
Data Retention (Extended Temp)		20	years

CAPACITANCE (T_A = +25°C, F = 1.0MHz)

Parameter	Symbol	Max	Unit
OE capacitance	COE	50	pF
WE1-4 capacitance			
HIP (PGA)	CWE	20	pF
HIP (Alternate pinout)	CWE	50	pF
CQFP G4T	CWE	50	pF
CQFP G2U	CWE	20	pF
G2U (Alternate pinout)	CWE	50	pF
CS1-4 capacitance	CCS	20	pF
Data I/O capacitance	CI/O	20	pF
Address input capacitance	CAD	50	pF

This parameter is guaranteed by design but not tested.

RECOMMENDED DC OPERATING CONDITIONS

Parameter	Symbol	Min	Typ	Max	Unit
Supply Voltage	V _{CC}	4.5	5.0	5.5	V
Ground	V _{SS}	0	0	0	V
Input High Voltage	V _{IH}	2.0	-	V _{CC} + 0.5	V
Input Low Voltage	V _{IL}	-0.5	-	+0.8	V
Operating Temperature (Ext.)(4)	T _A	-55	-	+100	°C
Operating Temperature (Ind.)	T _A	-40	-	+85	°C

DC CHARACTERISTICS - CMOS COMPATIBLE (V_{CC} = 5.0V, V_{SS} = 0V, T_A = -55°C to +125°C) (Note 4)

Parameter	Symbol	Conditions	Min	Max	Unit
Input Leakage Current	I _{LI}	V _{CC} = 5.5, V _{IN} = GND to V _{CC}		10	µA
Output Leakage Current	I _{LOx2}	V _{CC} = 5.5, V _{IN} = GND to V _{CC}		10	µA
V _{CC} Active Current for Read (1)	I _{CC1}	$\overline{CS} = V_{IL}, \overline{OE} = V_{IH}, f = 5\text{MHz}$		160	mA
V _{CC} Active Current for Program or Erase (2)	I _{CC2}	$\overline{CS} = V_{IL}, \overline{OE} = V_{IH}$		240	mA
V _{CC} Standby Current	I _{CC3}	V _{CC} = 5.5, $\overline{CS} = V_{IH}, f = 5\text{MHz}, \overline{RESET} = V_{CC} \pm 0.3\text{V}$		8.0	mA
Output Low Voltage	V _{OL}	I _{OL} = 12.0 mA, V _{CC} = 4.5		0.45	V
Output High Voltage	V _{OH}	I _{OH} = -2.5 mA, V _{CC} = 4.5	0.85xV _{CC}		V
Low V _{CC} Lock-Out Voltage	V _{LKO}		3.2	4.2	V

NOTES:

- The I_{CC} current listed includes both the DC operating current and the frequency dependent component (@ 5MHz). The frequency component typically is less than 2mA/MHz, with OE at V_{IH}.
- I_{CC} active while Embedded Algorithm (program or erase) is in progress.
- DC test conditions V_{IL} = 0.3V, V_{IH} = V_{CC} - 0.3V
- Extended temperature devices are fully operational from -55°C to +100°C. Operation above 100°C to 125°C is limited to read-only operation.



AC CHARACTERISTICS – WRITE/ERASE/PROGRAM OPERATIONS – \overline{WE} CONTROLLED (VCC = 5.0V, TA = -55°C to +125°C) (Note 6)

Parameter	Symbol		-90		-120		-150		Unit
			Min	Max	Min	Max	Min	Max	
Write Cycle Time	tAVAV	tWC	90		120		150		ns
Chip Select Setup Time	tELWL	tCS	0		0		0		ns
Write Enable Pulse Width	tWLWH	tWP	45		50		50		ns
Address Setup Time	tAVWL	tAS	0		0		0		ns
Data Setup Time	tDVWH	tDS	45		50		50		ns
Data Hold Time	tWHDX	tDH	0		0		0		ns
Address Hold Time	tWLAX	tAH	45		50		50		ns
Write Enable Pulse Width High	tWHWL	tWPH	20		20		20		ns
Duration of Byte Programming Operation (1)	tWHWH1			300		300		300	μs
Sector Erase (2)	tWHWH2			15		15		15	sec
Read Recovery Time before Write	tGHWL		0		0		0		μs
VCC Setup Time	tVCS		50		50		50		μs
Chip Programming Time				44		44		44	sec
Chip Erase Time (3)				256		256		256	sec
Output Enable Hold Time (4)		tOEHL	10		10		10		ns
\overline{RESET} Pulse Width (5)		tRP	500		500		500		ns

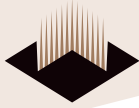
NOTES:

1. Typical value for tWHWH1 is 7μs.
2. Typical value for tWHWH2 is 1sec.
3. Typical value for Chip Erase Time is 32sec.
4. For Toggle and Data Polling.
5. \overline{RESET} internally tied to Vcc for the default pin configuration in the HIP package.
6. Extended temperature devices are fully operational from -55°C to +100°C. Operation above 100°C to 125°C is limited to read-only operation.

AC CHARACTERISTICS – READ-ONLY OPERATIONS (VCC = 5.0V, TA = -55°C to +125°C) (Note 3)

Parameter	Symbol		-90		-120		-150		Unit
			Min	Max	Min	Max	Min	Max	
Read Cycle Time	tAVAV	tRC	90		120		150		ns
Address Access Time	tAVQV	tACC		90		120		150	ns
Chip Select Access Time	tELQV	tCE		90		120		150	ns
Output Enable to Output Valid	tGLQV	tOE		40		50		55	ns
Chip Select High to Output High Z (1)	tEHQZ	tDF		20		30		35	ns
Output Enable High to Output High Z (1)	tGHQZ	tDF		20		30		35	ns
Output Hold from Addresses, \overline{CS} or \overline{OE} Change, whichever is First	tAXQX	tOH	0		0		0		ns
RST Low to Read Mode (1,2)		tReady		20		20		20	μs

1. Guaranteed by design, not tested.
2. \overline{RESET} internally tied to Vcc for the default pin configuration in the HIP package.
3. Extended temperature devices are fully operational from -55°C to +100°C. Operation above 100°C to 125°C is limited to read-only operation.



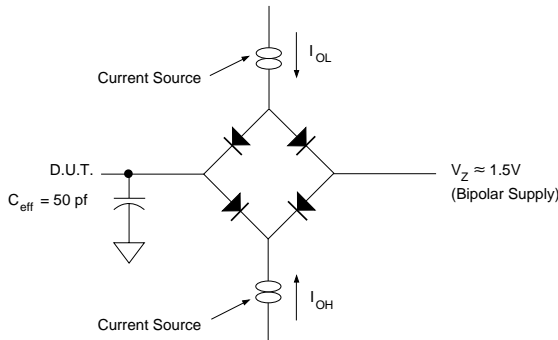
AC CHARACTERISTICS – WRITE/ERASE/PROGRAM OPERATIONS, \overline{CS} CONTROLLED
 (VCC = 5.0V, VSS = 0V, TA = -55°C to +125°C) (Note 5)

Parameter	Symbol		-90		-120		-150		Unit
			Min	Max	Min	Max	Min	Max	
Write Cycle Time	t _{AVAV}	t _{WC}	90		120		150		ns
Write Enable Setup Time	t _{WLEL}	t _{WS}	0		0		0		ns
Chip Select Pulse Width	t _{ELEH}	t _{CP}	45		50		50		ns
Address Setup Time	t _{AVEL}	t _{AS}	0		0		0		ns
Data Setup Time	t _{DVEH}	t _{DS}	45		50		50		ns
Data Hold Time	t _{EHDX}	t _{DH}	0		0		0		ns
Address Hold Time	t _{ELAX}	t _{AH}	45		50		50		ns
Chip Select Pulse Width High	t _{EHLE}	t _{CPH}	20		20		20		ns
Duration of Byte Programming Operation (1)	t _{WHWH1}			300		300		300	μs
Sector Erase Time (2)	t _{WHWH2}			15		15		15	sec
Read Recovery Time	t _{GHLE}		0		0		0		μs
Chip Programming Time				44		44		44	sec
Chip Erase Time (3)				256		256		256	sec
Output Enable Hold Time (4)		t _{OEH}	10		10		10		ns

NOTES:

1. Typical value for t_{WHWH1} is 7μs.
2. Typical value for t_{WHWH2} is 1sec.
3. Typical value for Chip Erase Time is 32sec.
4. For Toggle and Data Polling.
5. Extended temperature devices are fully operational from -55°C to +100°C. Operation above 100°C to 125°C is limited to read-only operation.

FIG. 3
AC TEST CIRCUIT



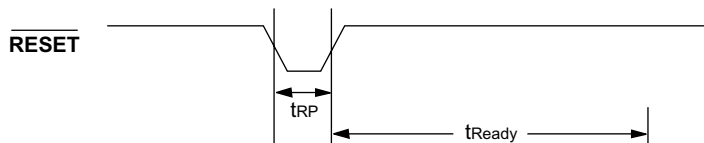
AC TEST CONDITIONS

Parameter	Typ	Unit
Input Pulse Levels	V _{IL} = 0, V _{IH} = 3.0	V
Input Rise and Fall	5	ns
Input and Output Reference Level	1.5	V
Output Timing Reference Level	1.5	V

Notes:

V_Z is programmable from -2V to +7V.
 I_{OL} & I_{OH} programmable from 0 to 16mA.
 Tester Impedance Z₀ = 75 Ω.
 V_Z is typically the midpoint of V_{OH} and V_{OL}.
 I_{OL} & I_{OH} are adjusted to simulate a typical resistive load circuit.
 ATE tester includes jig capacitance.

FIG. 4
RESET TIMING DIAGRAM



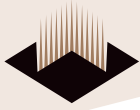


FIG. 5
AC WAVEFORMS FOR READ OPERATIONS

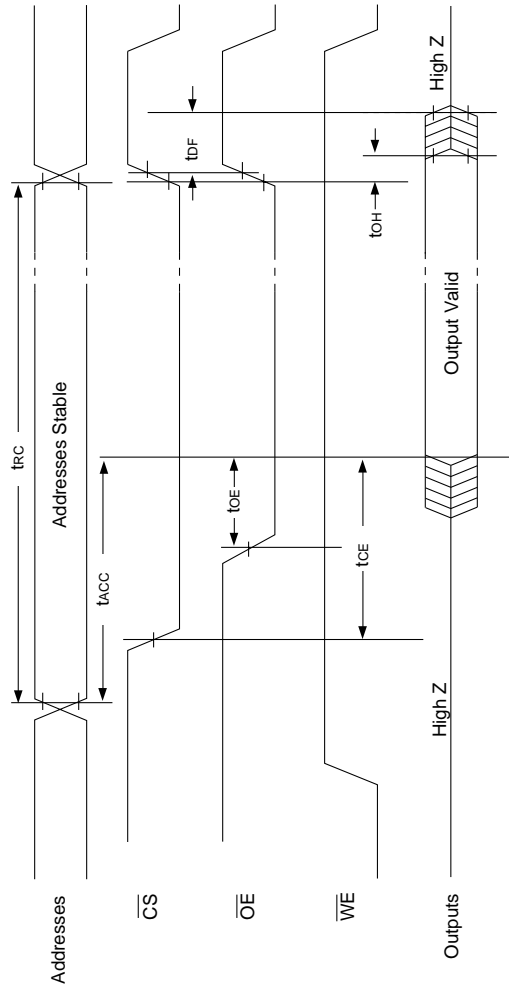
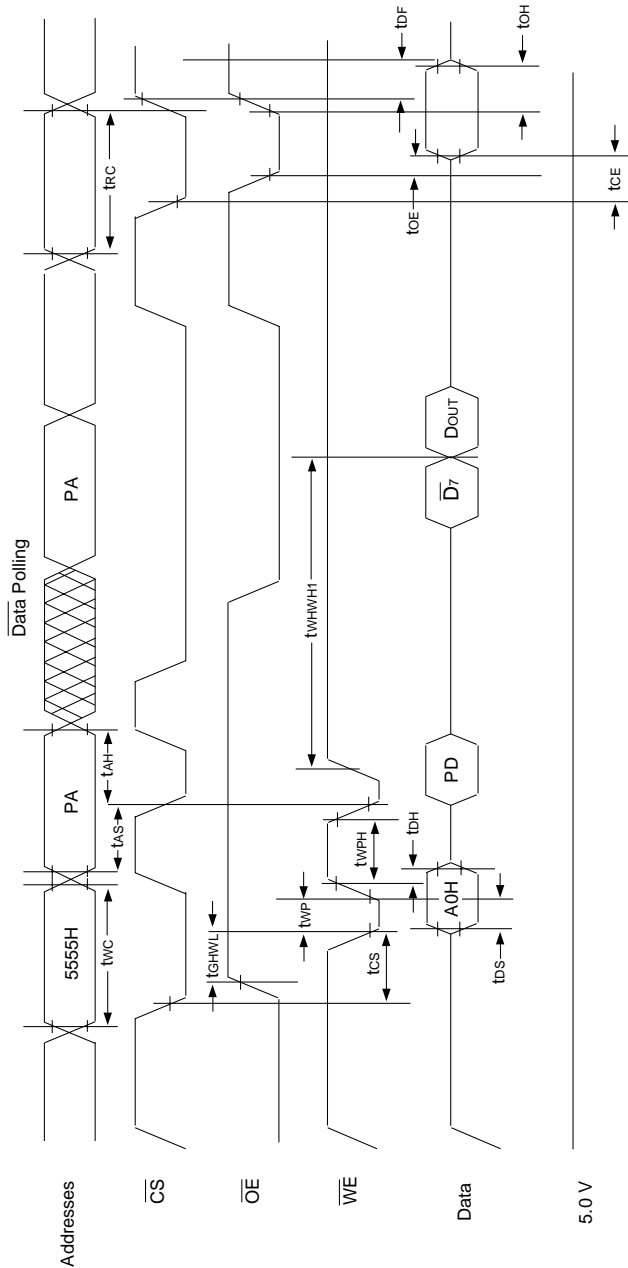




FIG. 6
WRITE/ERASE/PROGRAM
OPERATION, WE CONTROLLED

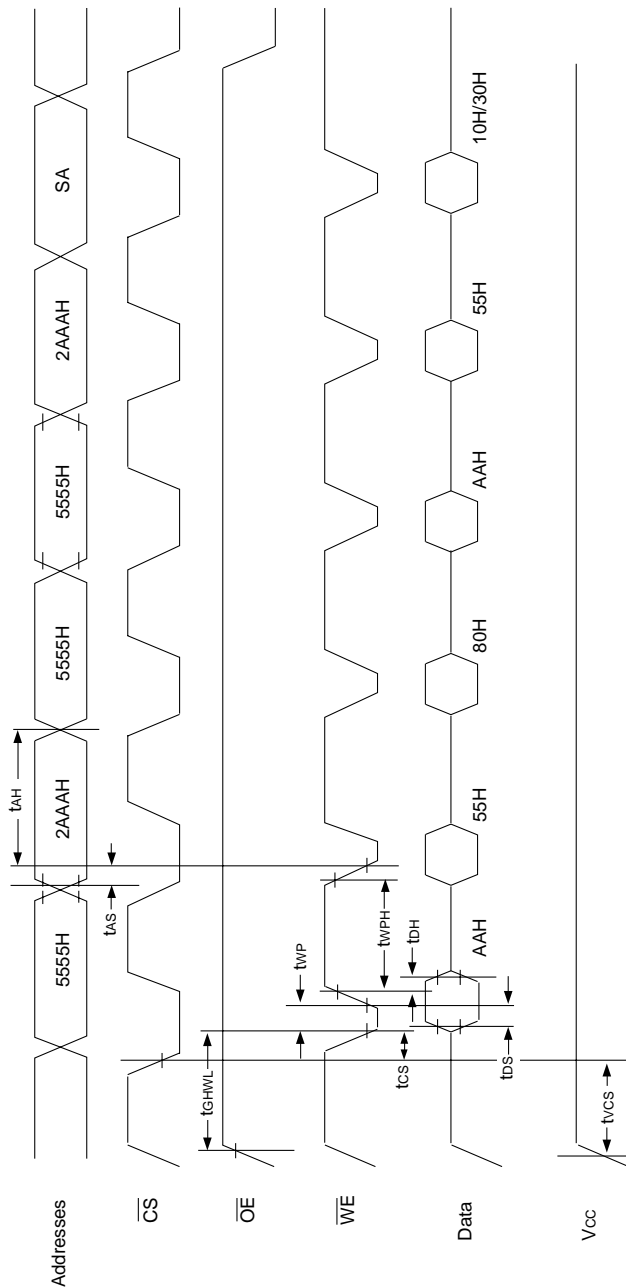


NOTES:

1. PA is the address of the memory location to be programmed.
2. PD is the data to be programmed at byte address.
3. $\overline{D7}$ is the output of the complement of the data written to each chip.
4. Dout is the output of the data written to the device.
5. Figure indicates last two bus cycles of four bus cycle sequence.



FIG. 7
AC WAVEFORMS CHIP/SECTOR
ERASE OPERATIONS

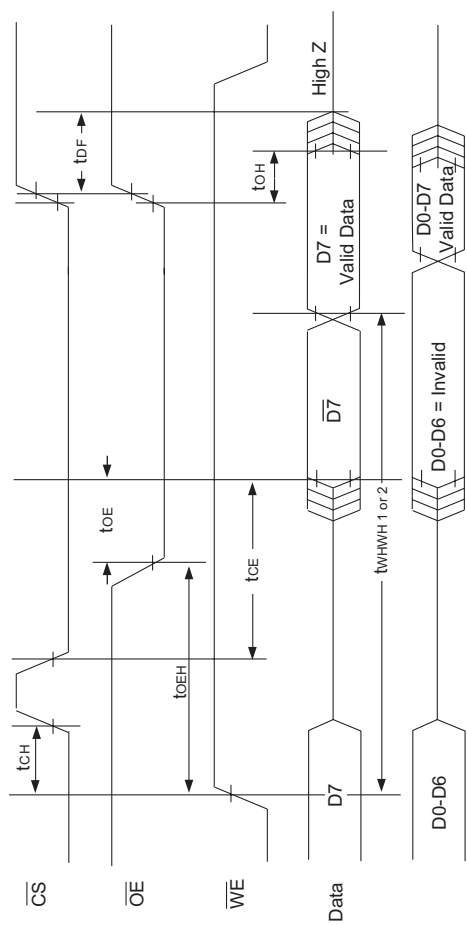


NOTE:

1. SA is the sector address for Sector Erase.



FIG. 8
AC WAVEFORMS FOR DATA POLLING
DURING EMBEDDED ALGORITHM OPERATIONS



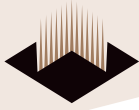
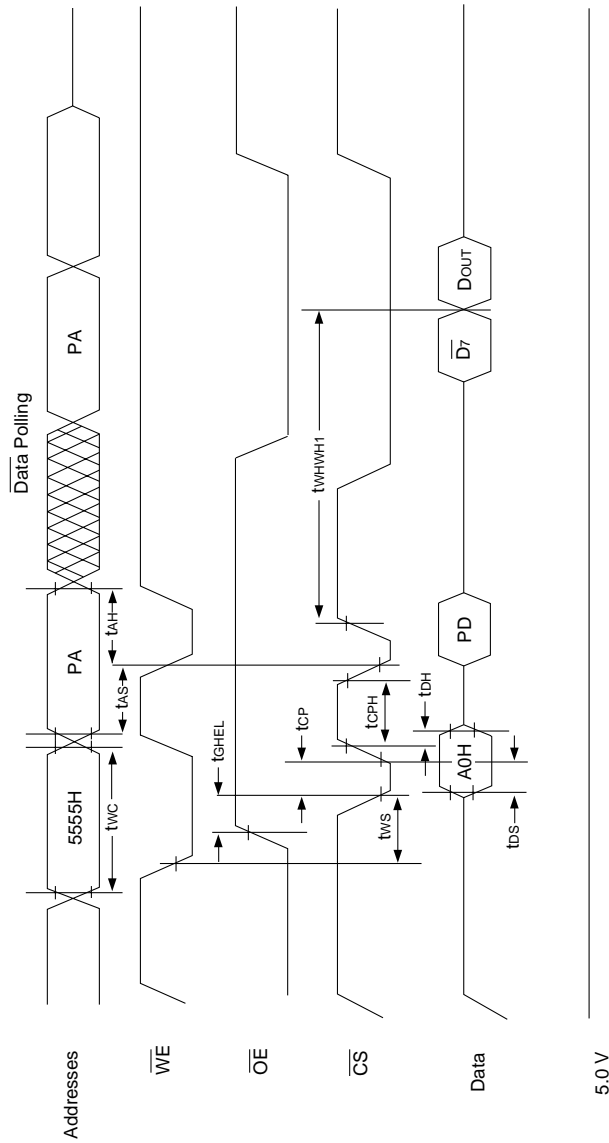


FIG. 9
ALTERNATE \overline{CS} CONTROLLED
PROGRAMMING OPERATION TIMINGS



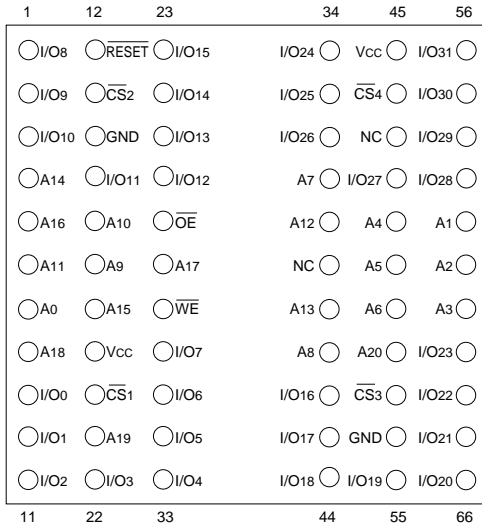
Notes:

1. PA represents the address of the memory location to be programmed.
2. PD represents the data to be programmed at byte address.
3. $\overline{D7}$ is the output of the complement of the data written to each chip.
4. D_{OUT} is the output of the data written to the device.
5. Figure indicates the last two bus cycles of a four bus cycle sequence.



FIG. 10 ALTERNATE PIN CONFIGURATION FOR WF2M32I-XHX5

TOP VIEW



PIN DESCRIPTION

I/O0-31	Data Inputs/Outputs
A0-20	Address Inputs
WE	Write Enable
CS1-4	Chip Selects
OE	Output Enable
Vcc	Power Supply
GND	Ground
RESET	Reset

BLOCK DIAGRAM

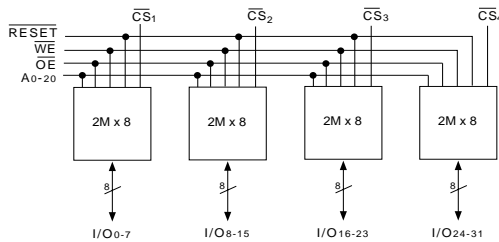
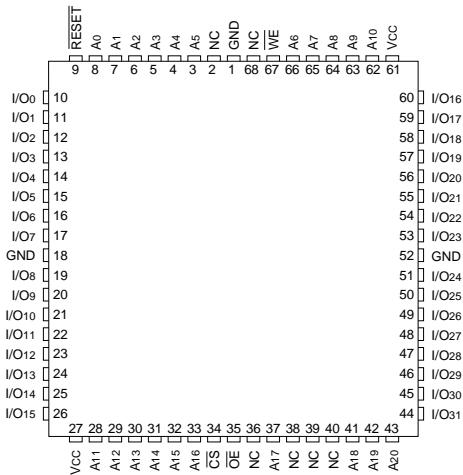


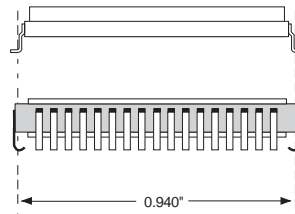
FIG. 11 ALTERNATE PIN CONFIGURATION FOR WF2M32U-XG2UX5

TOP VIEW



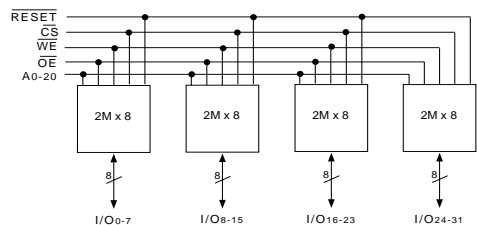
PIN DESCRIPTION

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CS	Chip Select
OE	Output Enable
Vcc	Power Supply
GND	Ground
RESET	Reset



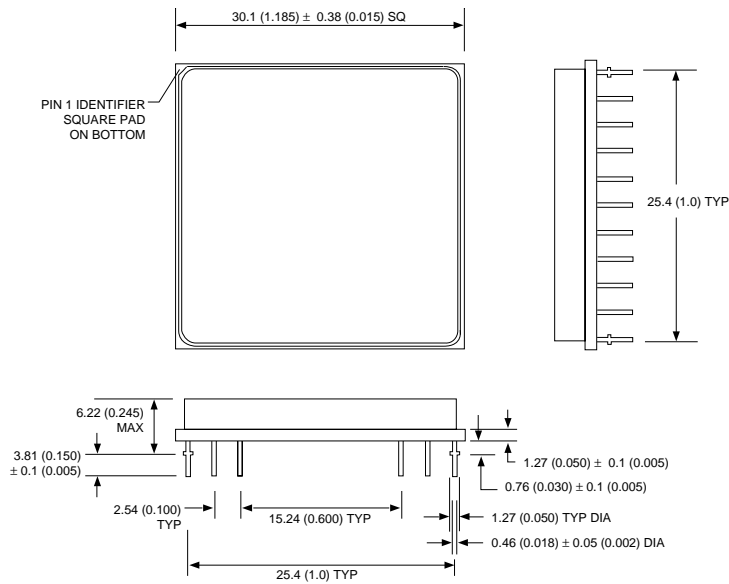
The WEDC 68 lead G2U CQFP fills the same fit and function as the JEDEC 68 lead CQFJ or 68 PLCC. But the G2U has the TCE and lead inspection advantage of the CQFP form.

BLOCK DIAGRAM

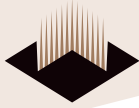




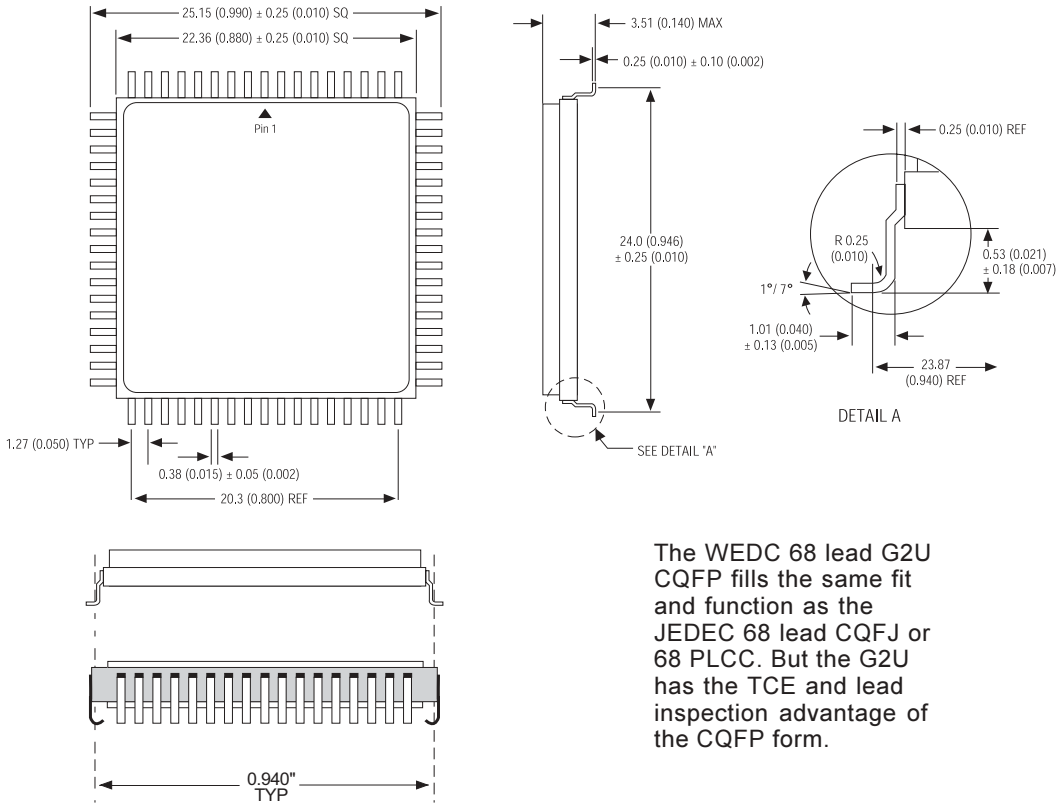
PACKAGE 401: 66 PIN, PGA TYPE, CERAMIC HEX-IN-LINE PACKAGE, HIP (H)



ALL LINEAR DIMENSIONS ARE MILLIMETERS AND PARENTHETICALLY IN INCHES



PACKAGE 510: 68 LEAD, CERAMIC QUAD FLAT PACK, CQFP (G2U)



The WEDC 68 lead G2U CQFP fills the same fit and function as the JEDEC 68 lead CQFJ or 68 PLCC. But the G2U has the TCE and lead inspection advantage of the CQFP form.

ALL LINEAR DIMENSIONS ARE MILLIMETERS AND PARENTHETICALLY IN INCHES



ORDERING INFORMATION

W F 2M32 X - XXX X X 5 X

LEAD FINISH:

- Blank = Gold plated leads
- A = Solder dip leads

V_{PP} PROGRAMMING VOLTAGE

5 = 5 V

DEVICE GRADE:

- QE = Compliant -55°C to +100°C (Note 1)
- E = Extended -55°C to +100°C (Note 1)
- I = Industrial -40°C to +85°C
- C = Commercial 0°C to +70°C

PACKAGE TYPE:

- H = Ceramic Hex In line Package, HIP (Package 401)
- G2U = 22.4mm Ceramic Quad Flat Pack, CQFP (Package 510)

ACCESS TIME (ns)

IMPROVEMENT MARK

- For HIP Package
 - Blank = 4CS and 4WE
 - I = 4CS and 1WE, RESET
- For G2U Package
 - Blank = 4CS and 4WE
 - U = 1CS and 1WE

ORGANIZATION, 2M x 32

User configurable as 4M x 16 or 8M x 8 (Except WF2M32U-XG2UX which is 32 bit wide only.)

Flash

WHITE ELECTRONIC DESIGNS CORP.

Note:

1. Extended temperature devices are fully operational from -55°C to +100°C. Operation above 100°C to 125°C is limited to read-only operation.